

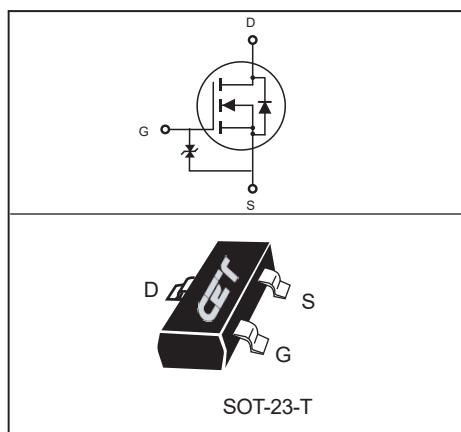
N-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

FEATURES

- High power and current handing capability.
- Reliable and rugged.
- Pb-free lead plating ; RoHS compliant.
- Halogen Free.

V_{DSS}	$R_{DS(ON)\text{ typ}} @ V_{GS}$	I_D
100V	112m Ω @ $V_{GS} = 10V$	2.1A

**ABSOLUTE MAXIMUM RATINGS** $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous@ $T_A = 25^\circ\text{C}$ @ $T_A = 70^\circ\text{C}$	I_D	2.1 1.7	A
Drain Current-Pulsed ^a	I_{DM}	8.4	A
Maximum Power Dissipation	P_D	1.25	W
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	100	$^\circ\text{C/W}$

**CEN2370E****Electrical Characteristics** $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 100\text{V}, V_{\text{GS}} = 0\text{V}$		1		μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$		10		μA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$		-10		μA
On Characteristics ^b						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	1		3	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 10\text{V}, I_D = 2\text{A}$		112	135	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 1\text{A}$		140	175	$\text{m}\Omega$
Dynamic Characteristics ^c						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 50\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		100		pF
Output Capacitance	C_{oss}			70		pF
Reverse Transfer Capacitance	C_{rss}			25		pF
Switching Characteristics ^c						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 50\text{V}, I_D = 2\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$		9.8		ns
Turn-On Rise Time	t_r			7.2		ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			14.6		ns
Turn-Off Fall Time	t_f			4.6		ns
Total Gate Charge	Q_g	$V_{\text{DS}} = 50\text{V}, I_D = 2\text{A}, V_{\text{GS}} = 4.5\text{V}$		2.4		nC
Gate-Source Charge	Q_{gs}			0.43		nC
Gate-Drain Charge	Q_{gd}			1.8		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S			1		A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_S = 1\text{A}$		1.2		V

Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
- b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
- c.Guaranteed by design, not subject to production testing.

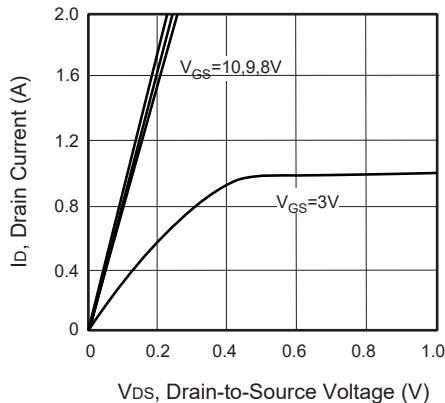


Figure 1. Output Characteristics

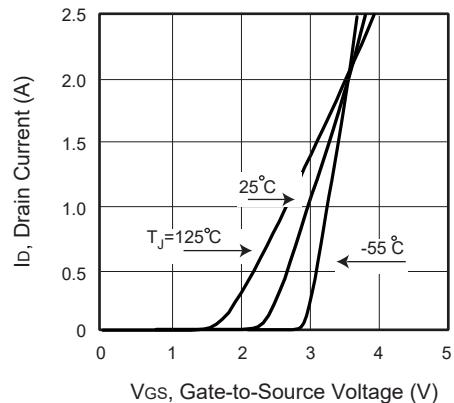


Figure 2. Transfer Characteristics

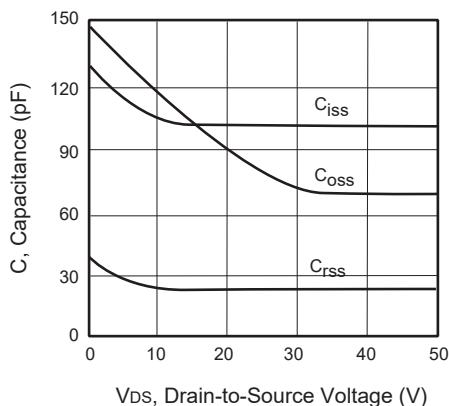


Figure 3. Capacitance

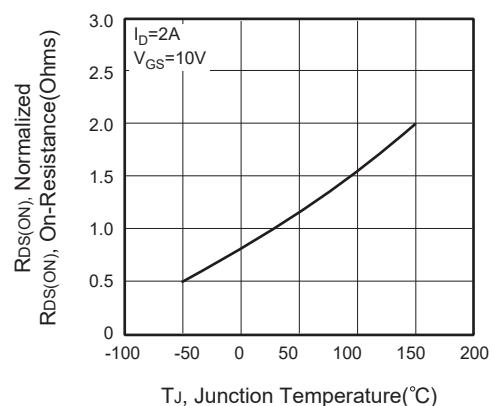


Figure 4. On-Resistance Variation with Temperature

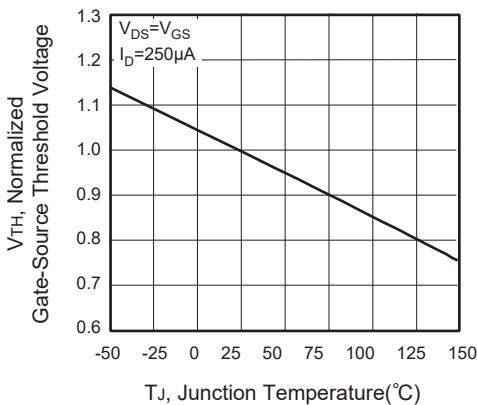


Figure 5. Gate Threshold Variation with Temperature

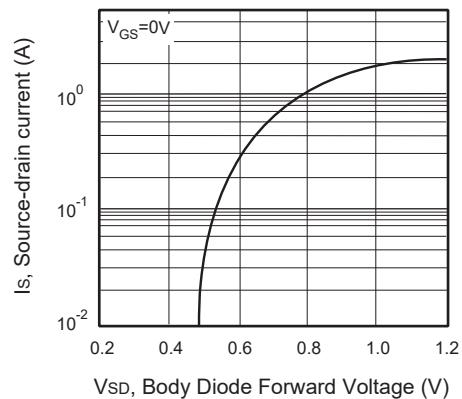


Figure 6. Body Diode Forward Voltage Variation with Source Current

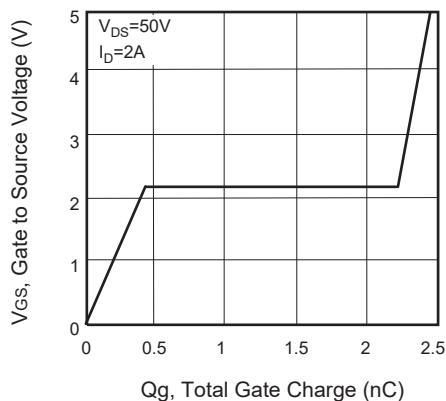


Figure 7. Gate Charge

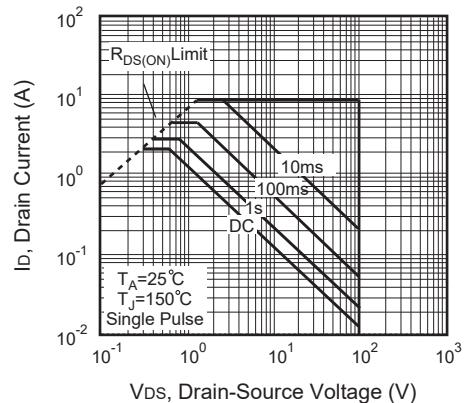


Figure 8. Maximum Safe Operating Area

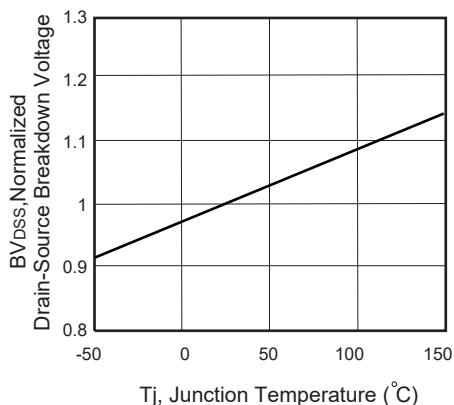


Figure 9. Breakdown Voltage Variation VS Temperature

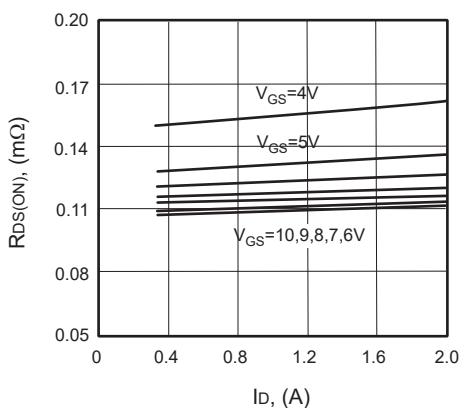


Figure 10. On-Resistance vs. Drain Current

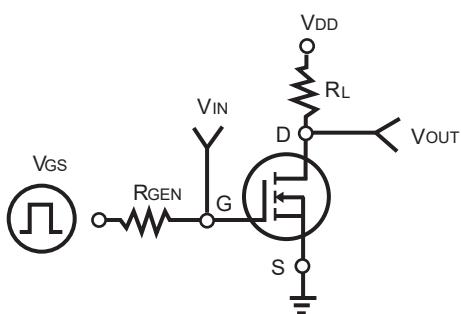


Figure 11. Switching Test Circuit

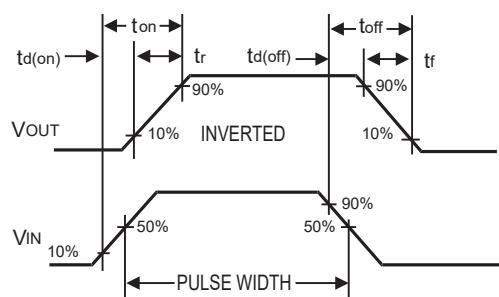


Figure 12. Switching Waveforms

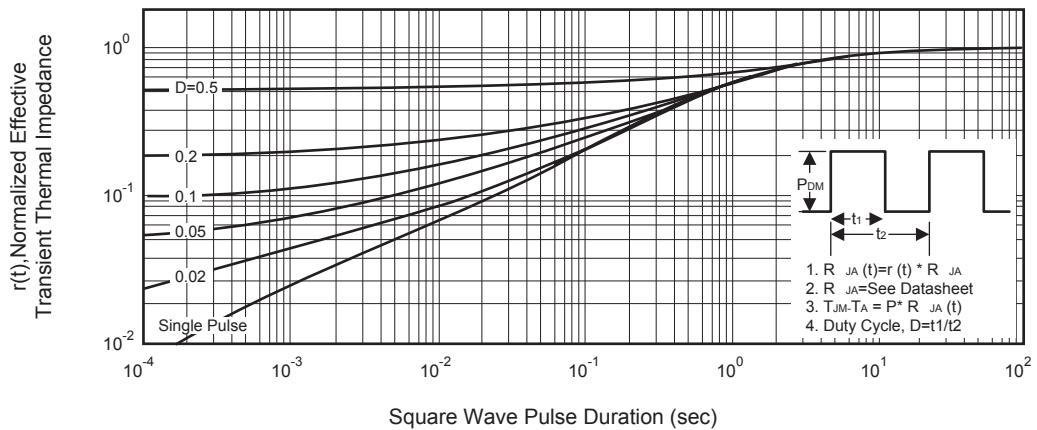


Figure 13. Normalized Thermal Transient Impedance Curve